

FIG. 1

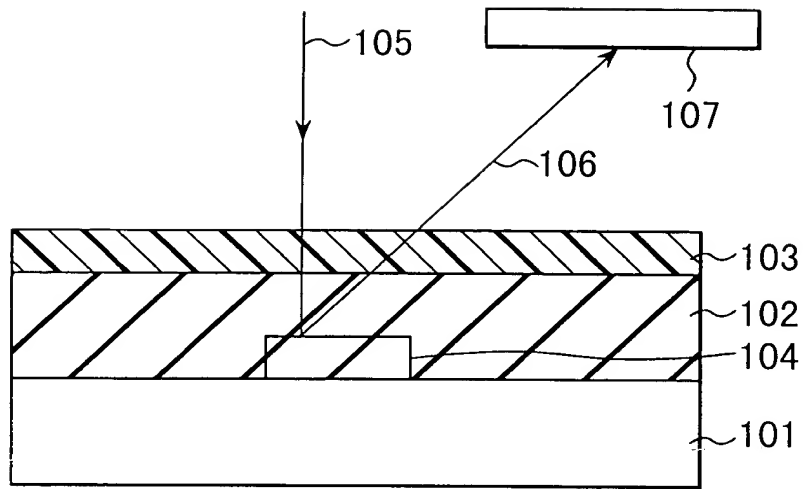


FIG. 3A

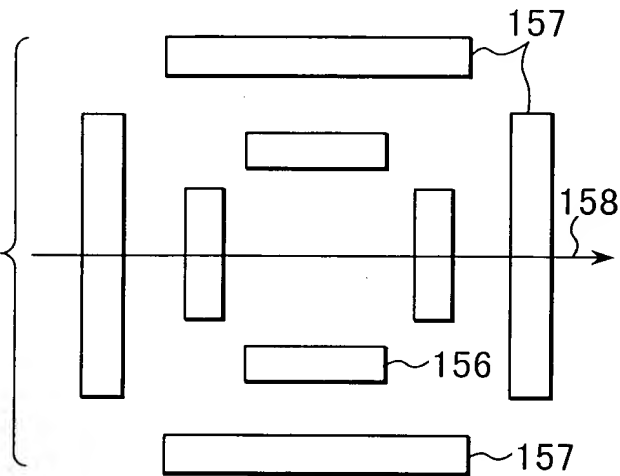
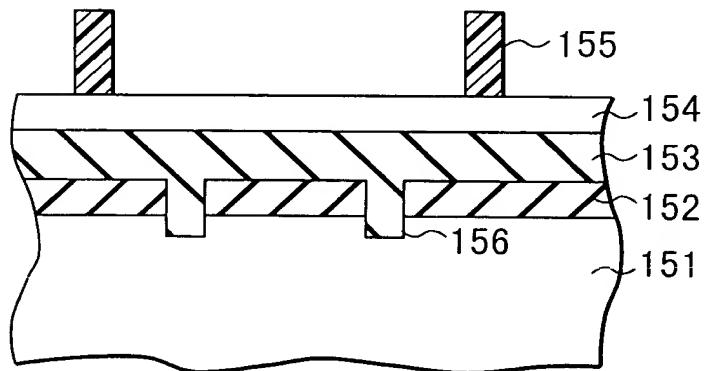


FIG. 3B



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FIG. 2A

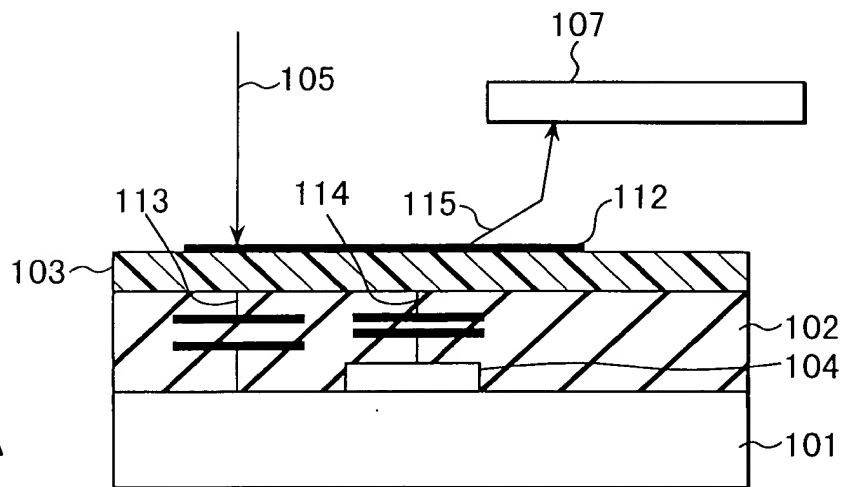


FIG. 2B

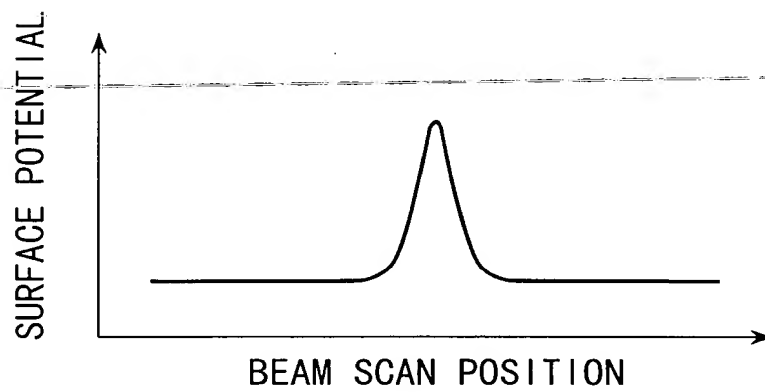


FIG. 2C

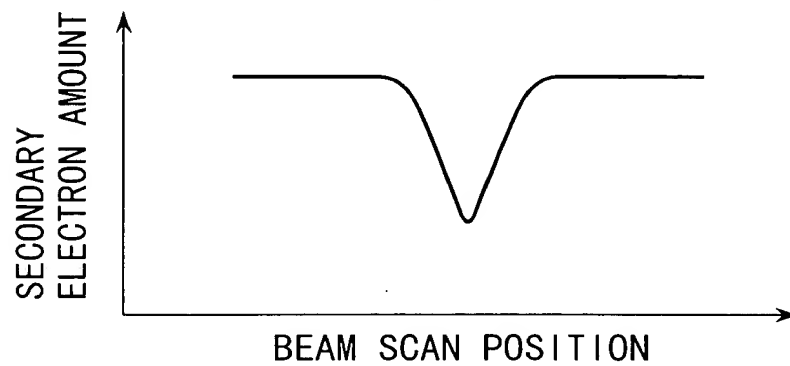


FIG. 2D

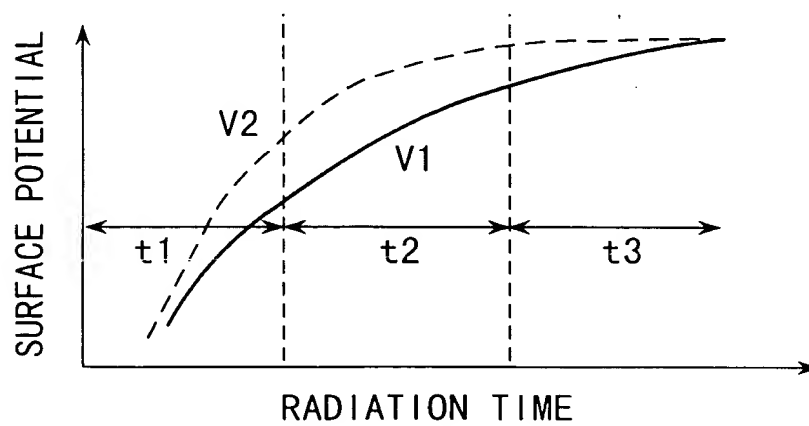


FIG. 4A

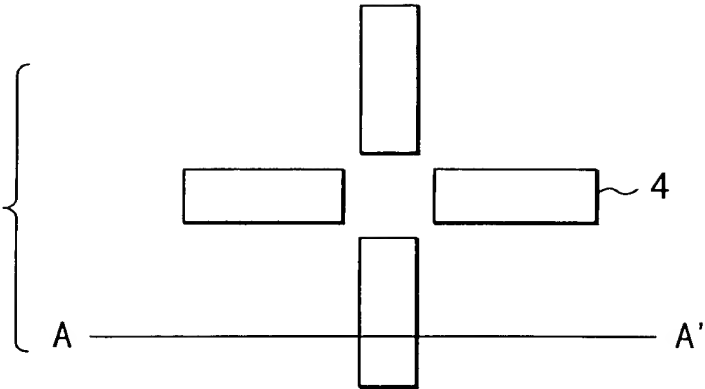
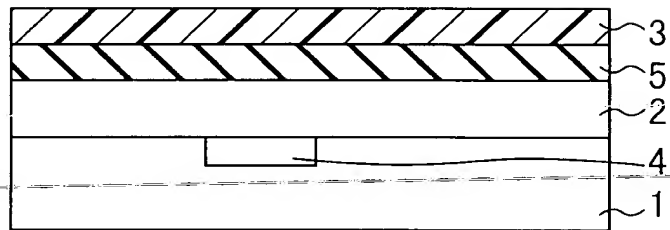


FIG. 4B



SHIFT MARK INTO DEFLECTION AREA

S1



SET FIRST RADIATION CONDITIONS

S2



FIRST BEAM EXPOSURE

S3



SET SECOND RADIATION CONDITIONS

S4



SECOND BEAM EXPOSURE

S5



ACQUIRE MARK IMAGE

S6



DETECT MARK POSITION

S7



DETERMINE PATTERN POSITION

S8



EXPOSURE

S9

FIG. 5

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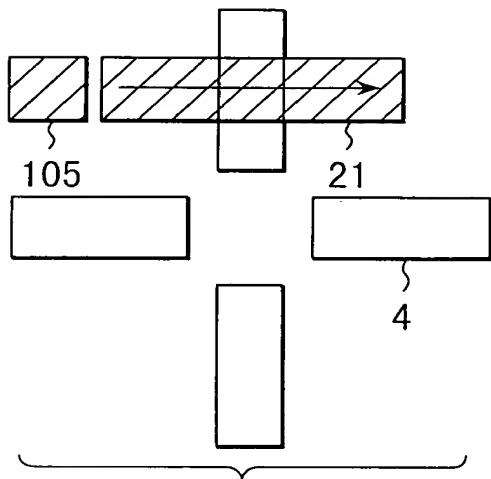


FIG. 6A

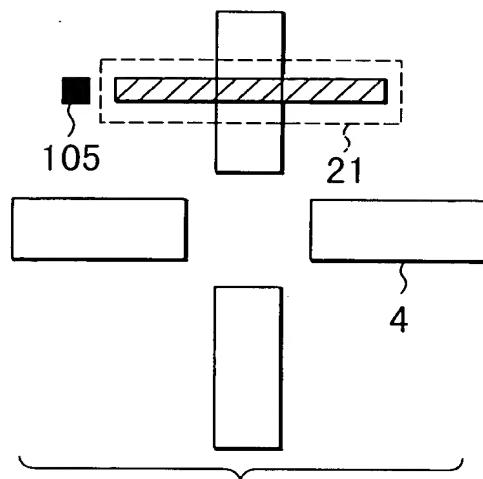


FIG. 6B

FIG. 7

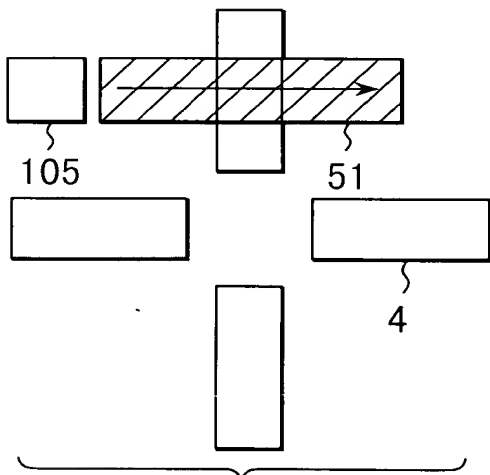
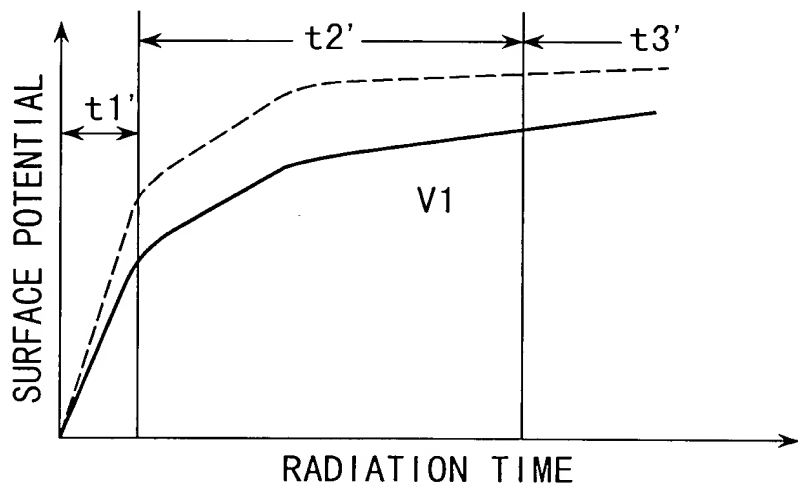


FIG. 8A

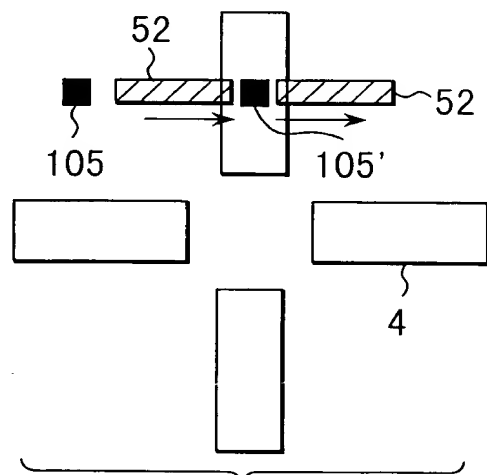


FIG. 8B

FIG. 9A

FIG. 9B

FIG. 9C

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FIG. 10A

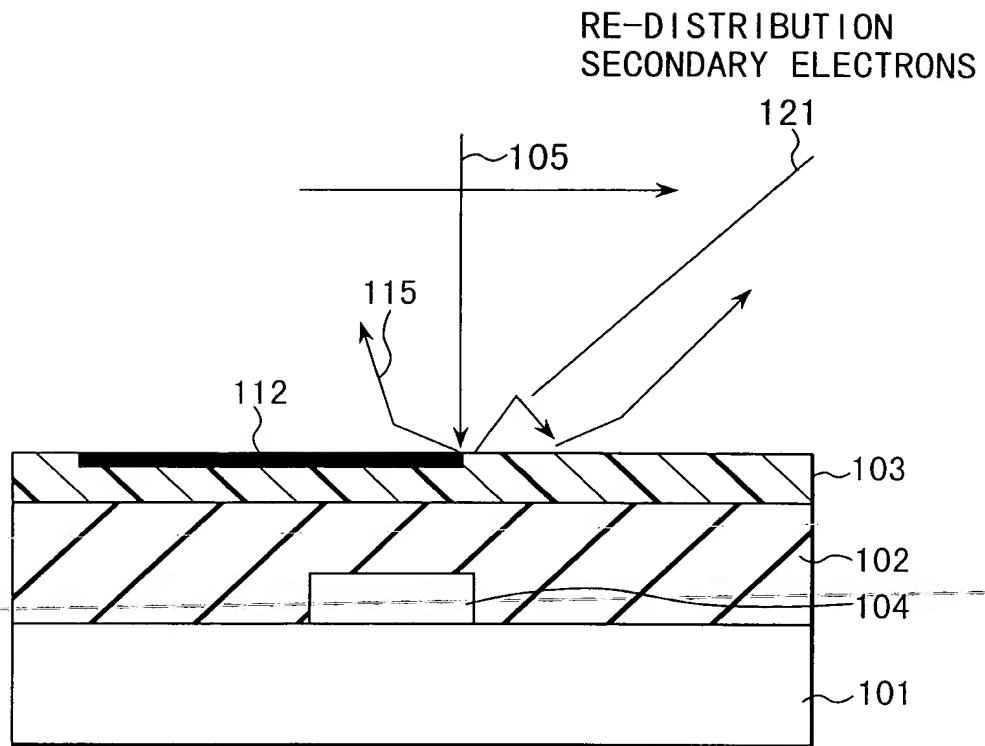


FIG. 10B

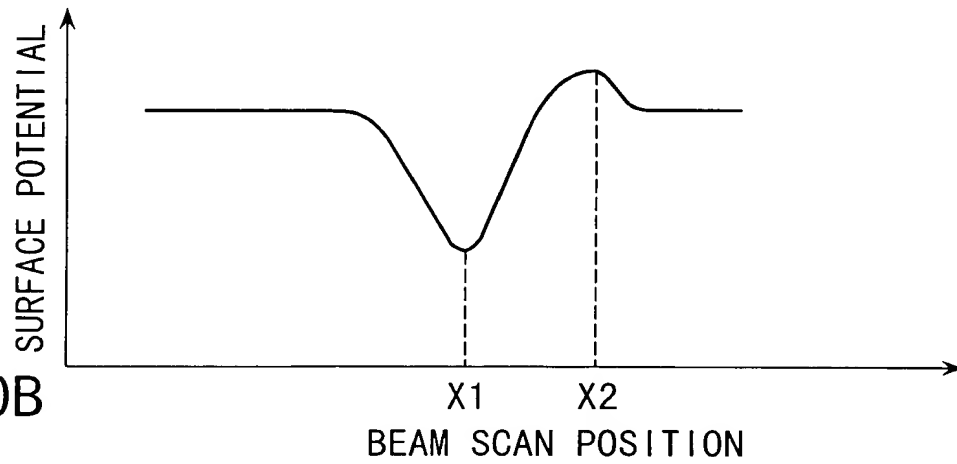
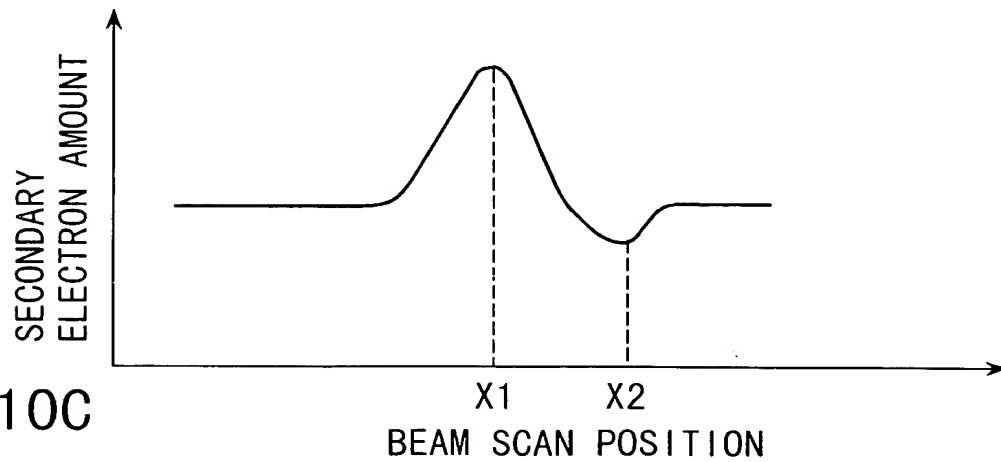


FIG. 10C



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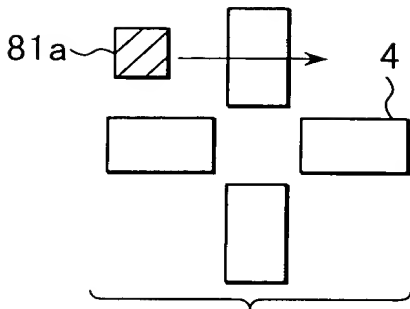


FIG. 11A

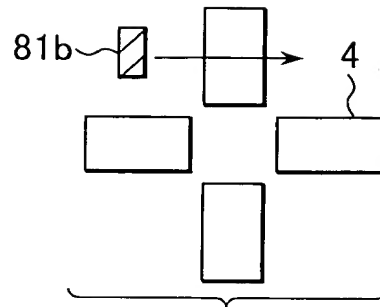


FIG. 11B

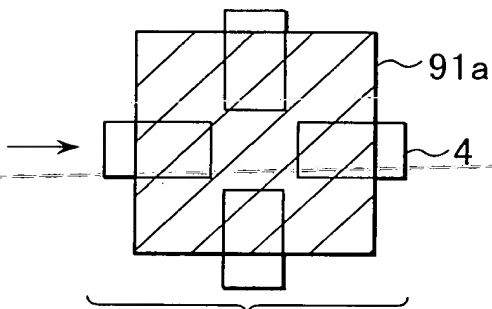


FIG. 12A

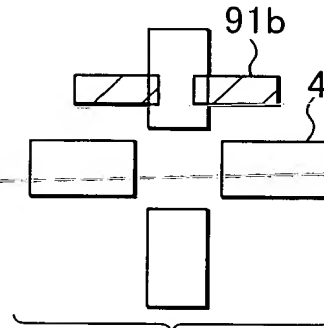
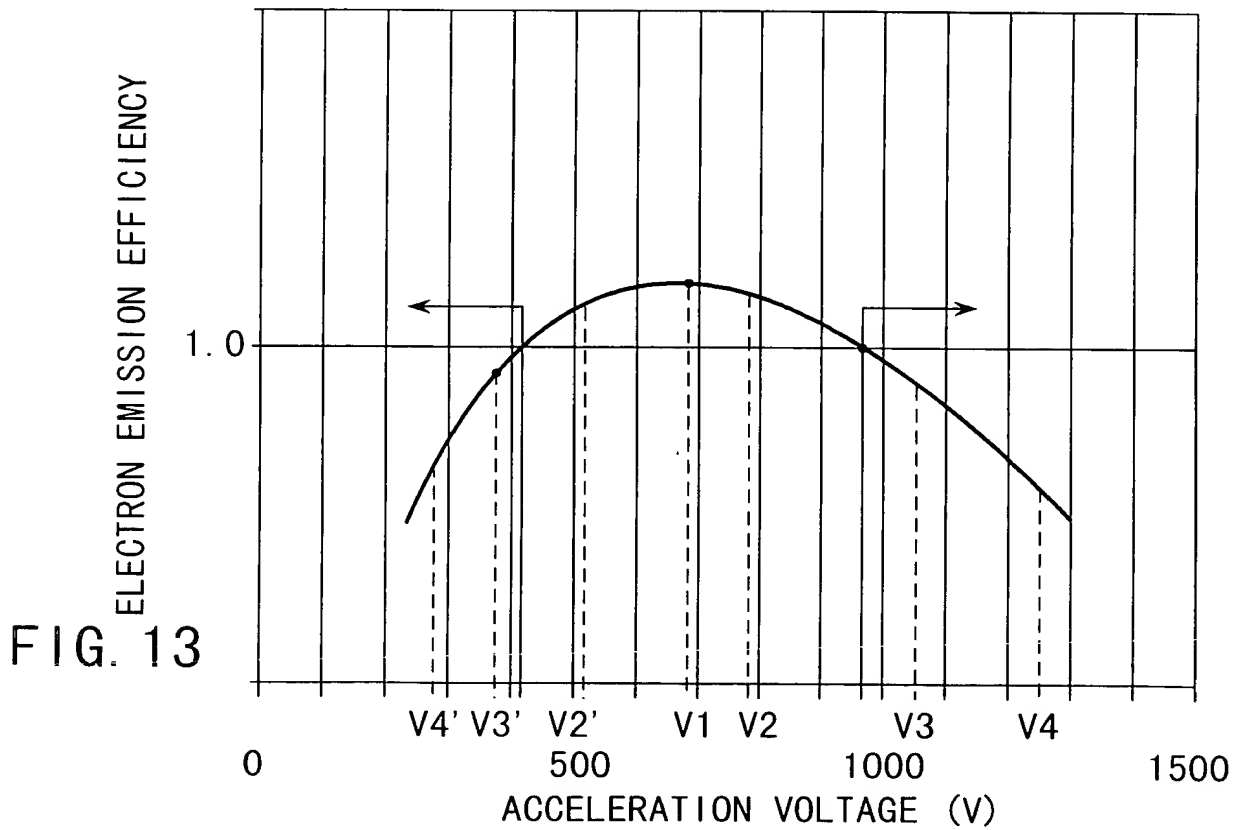


FIG. 12B



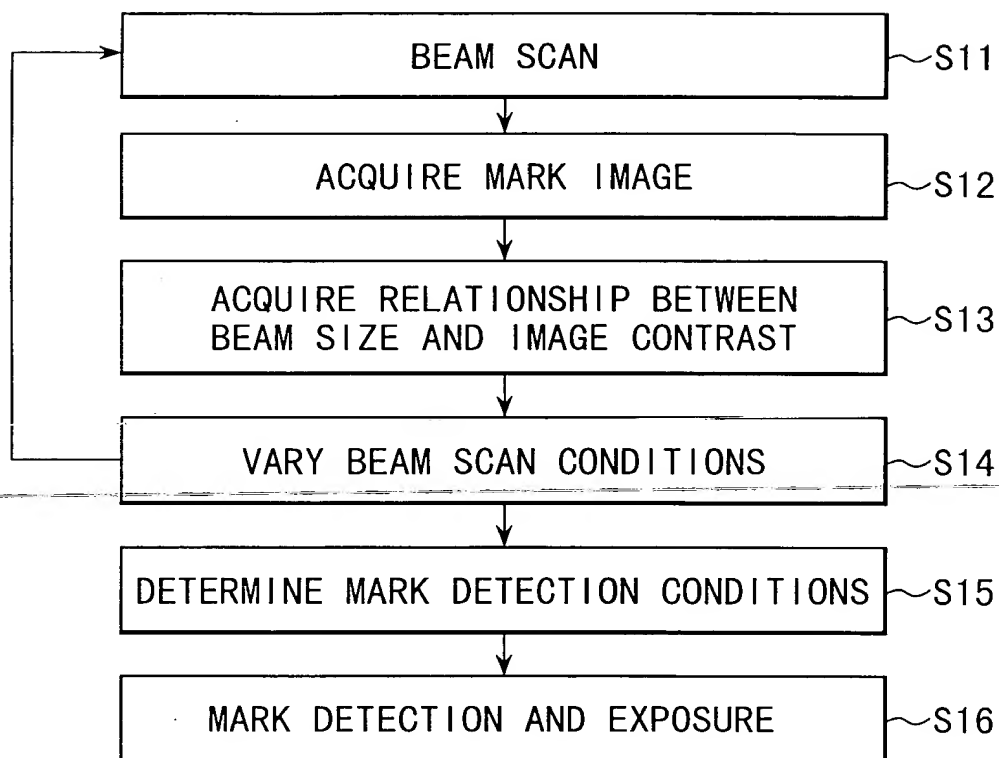


FIG. 14

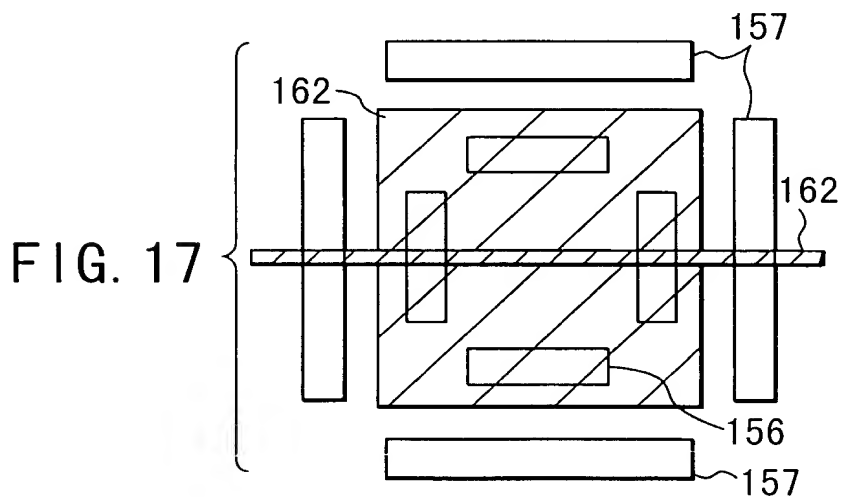


FIG. 17



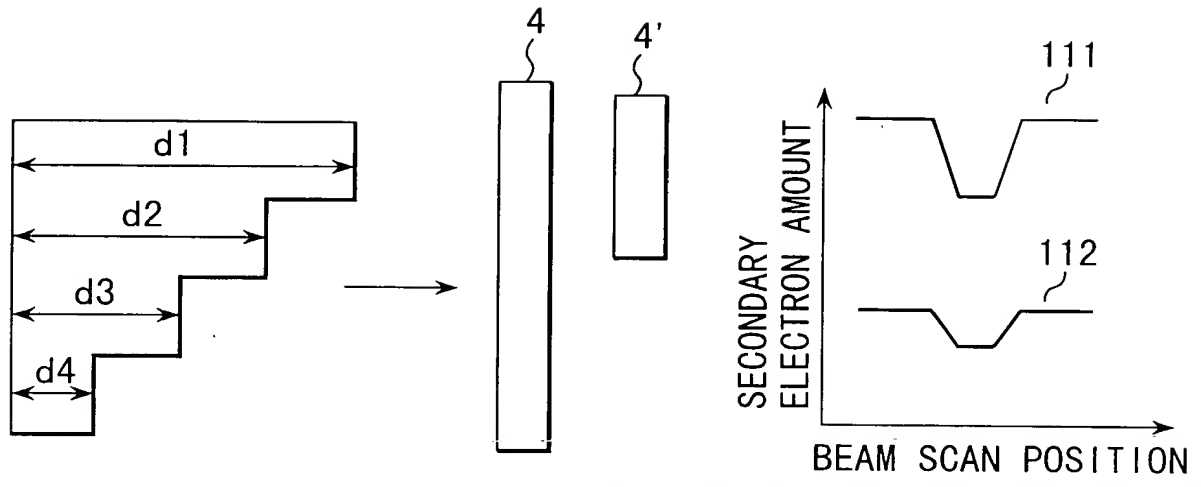


FIG. 15A

FIG. 15B

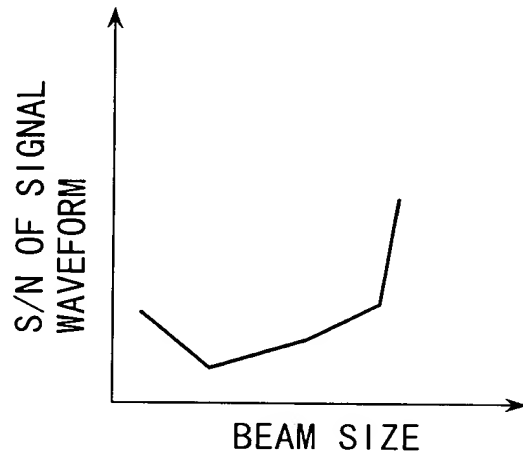


FIG. 15C

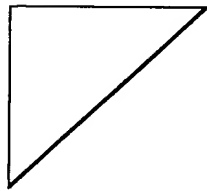
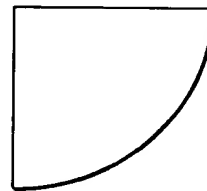
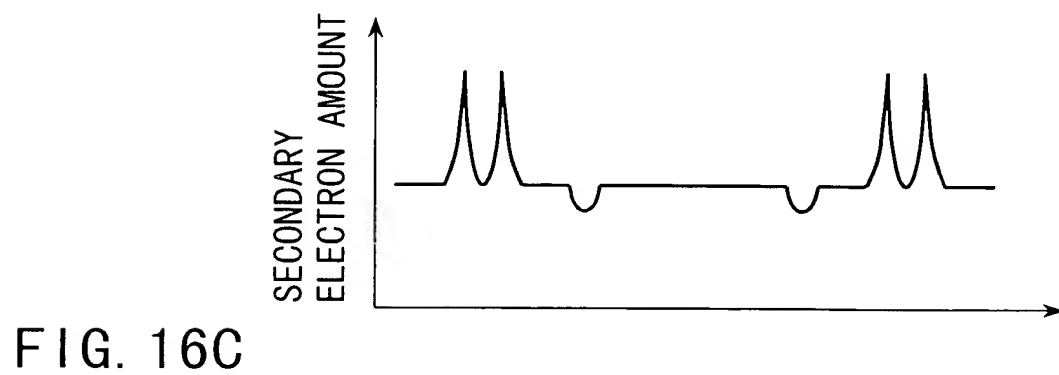
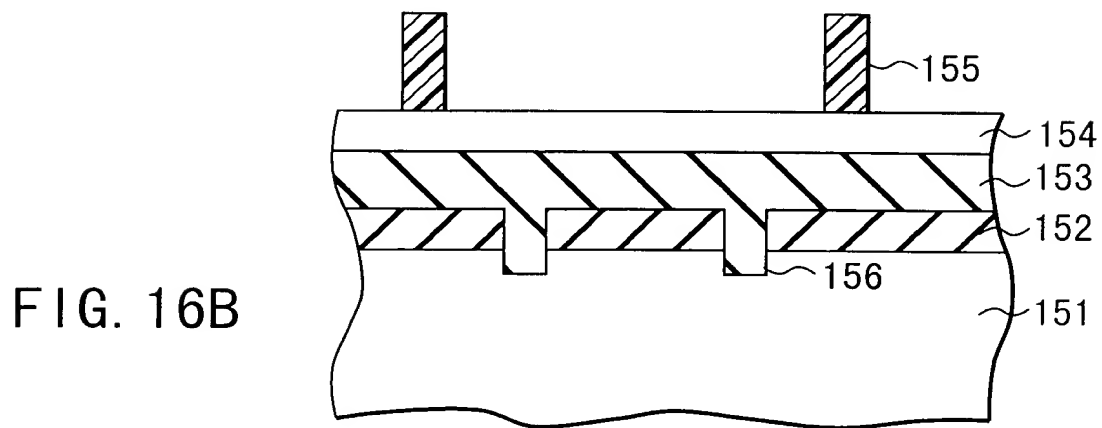
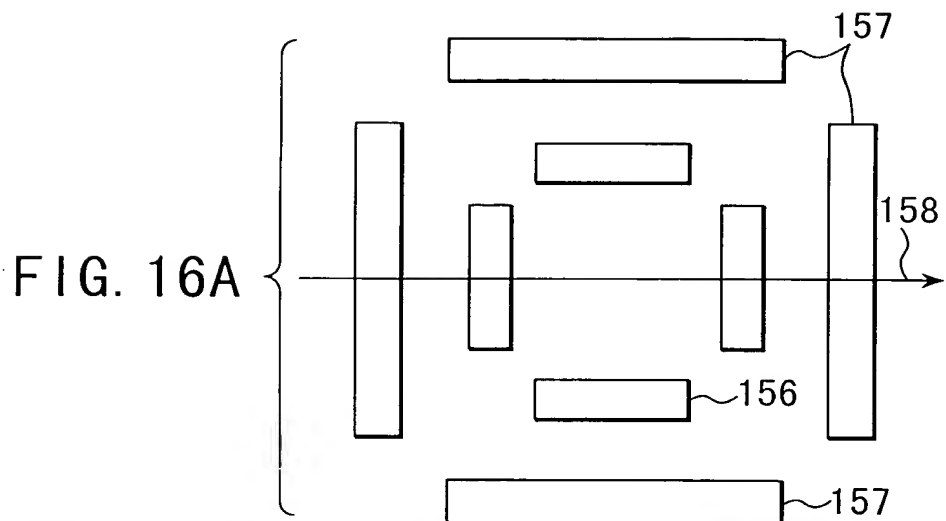


FIG. 15D



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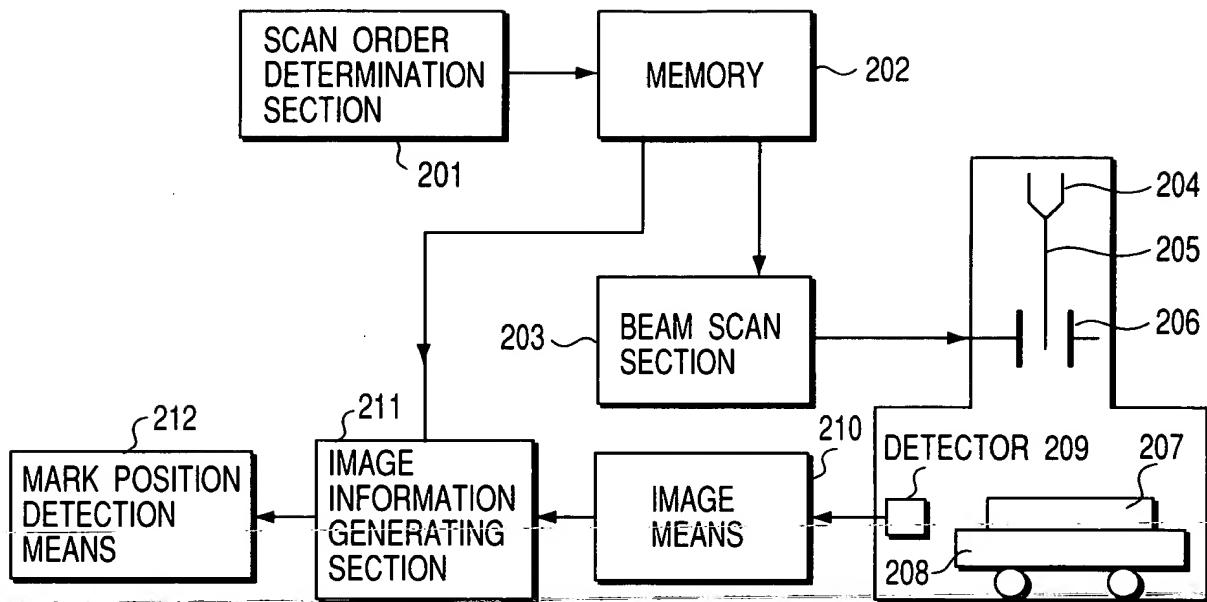


FIG. 18A

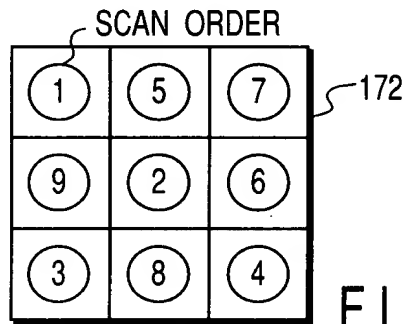


FIG. 18B

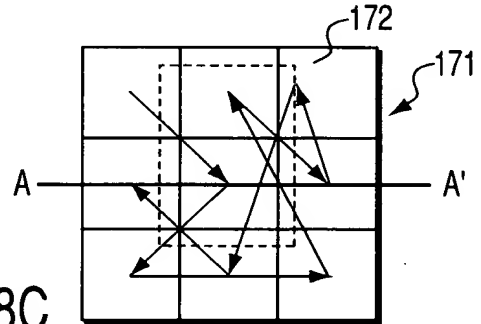


FIG. 18C

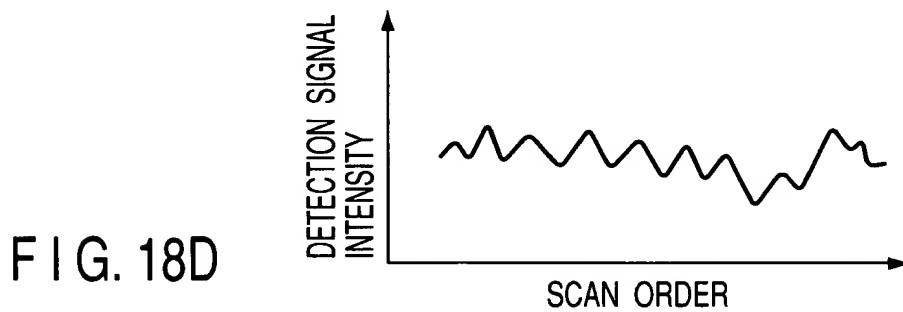


FIG. 18D

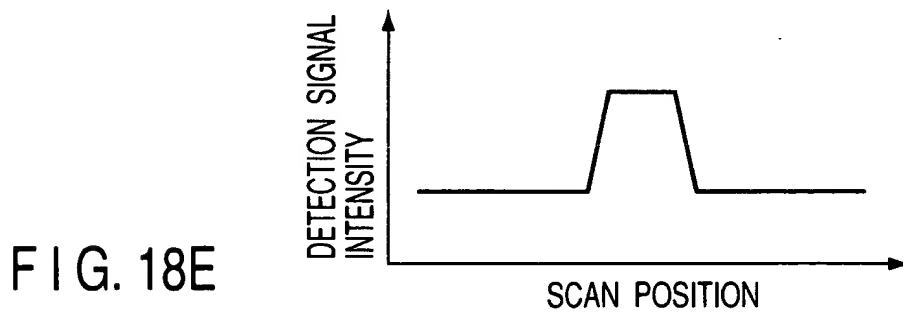


FIG. 18E